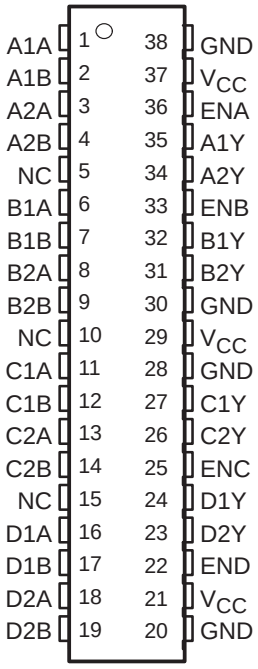
HIGH-SPEED DIFFERENTIAL LINE RECEIVERS

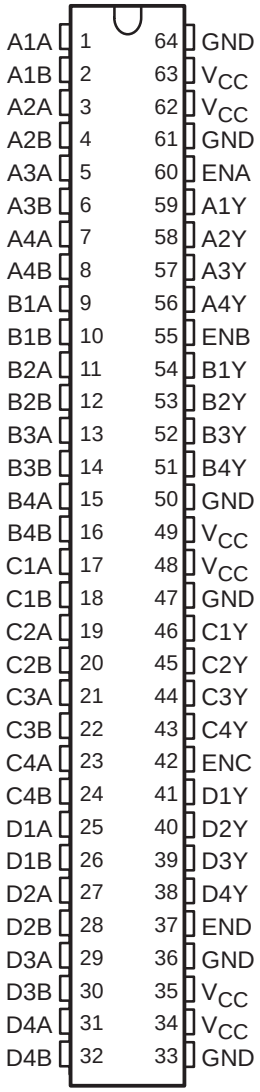
SLLS394A – SEPTEMBER 1999 – REVISED DECEMBER 1999

- **Eight (‘388) or Sixteen (‘386) Line Receivers Meet or Exceed the Requirements of ANSI TIA/EIA-644 Standard**
- **Integrated 110-Ω Line Termination Resistors on LVDT Products**
- **Designed for Signaling Rates† Up To 630 Mbps**
- **SN65 Version’s Bus-Terminal ESD Exceeds 15 kV**
- **Operates From a Single 3.3-V Supply**
- **Typical Propagation Delay Time of 2.6 ns**
- **Output Skew 100 ps (Typ)**
  Part-To-Part Skew is Less Than 1 ns
- **LVTTL Levels are 5-V Tolerant**
- **Open-Circuit Fail Safe**
- **Flow-Through Pin Out**
- **Packaged in Thin Shrink Small-Outline Package With 20-mil Terminal Pitch**

SN65LVDS388, SN75LVDS388
SN65LVDT388, SN75LVDT388
DBT PACKAGE
(TOP VIEW)



SN65LVDS386, SN75LVDS386
SN65LVDT386, SN75LVDT386
DGG PACKAGE
(TOP VIEW)



description

The ‘LVDS388 and ‘LVDT388 (*T* designates integrated termination) are eight and the ‘LVDS386 and ‘LVDT386 sixteen differential line receivers respectively that implement the electrical characteristics of low-voltage differential signaling (LVDS). This signaling technique lowers the output voltage levels of 5-V differential standard levels (such as EIA/TIA-422B) to reduce the power, increase the switching speeds, and allow operation with a 3-V supply rail. Any of the eight or sixteen differential receivers will provide a valid logical output state with a ±100 mV differential input voltage within the input common-mode voltage range. The input common-mode voltage range allows 1 V of ground potential difference between two LVDS nodes. Additionally, the high-speed switching of LVDS signals almost always require the use of a line impedance matching resistor at the receiving end of the cable or transmission media. The LVDT products eliminate this external resistor by integrating it with the receiver.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

† Signaling rate, 1/t, where t is the minimum unit interval and is expressed in the units bits/s (bits per second)

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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description (continued)

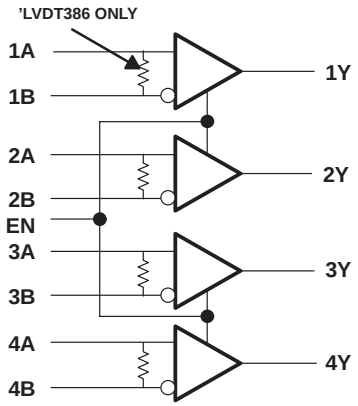
The intended application of this device and signaling technique is for point-to-point baseband data transmission over controlled impedance media of approximately 100 Ω. The transmission media may be printed circuit board traces, backplanes, or cables. The large number of receivers integrated into the same substrate along with the low pulse skew of balanced signaling, allows extremely precise timing alignment of clock and data for synchronous parallel data transfers. When used with its companion, 8- or 16-channel driver, the SN65LVDS389 or SN65LVDS387, over 300 million data transfers per second in single-edge clocked systems are possible with very little power. (Note: The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media, the noise coupling to the environment, and other system characteristics.)

Available Options

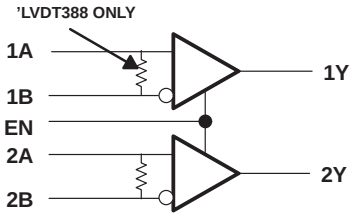
Part number	Temperature Range	Number of Receivers	Bus-Pin ESD
SN65LVDS386DGG	–40°C to 85°C	16	15 kV
SN65LVDT386DGG	–40°C to 85°C	16	15 kV
SN75LVDS386DGG	0°C to 70°C	16	4 kV
SN75LVDT386DGG	0°C to 70°C	16	4 kV
SN65LVDS388DBT	–40°C to 85°C	8	15 kV
SN65LVDT388DBT	–40°C to 85°C	8	15 kV
SN75LVDS388DBT	0°C to 70°C	8	4 kV
SN75LVDT388DBT	0°C to 70°C	8	4 kV

logic diagram (positive logic)

'LVDx386



'LVDx388



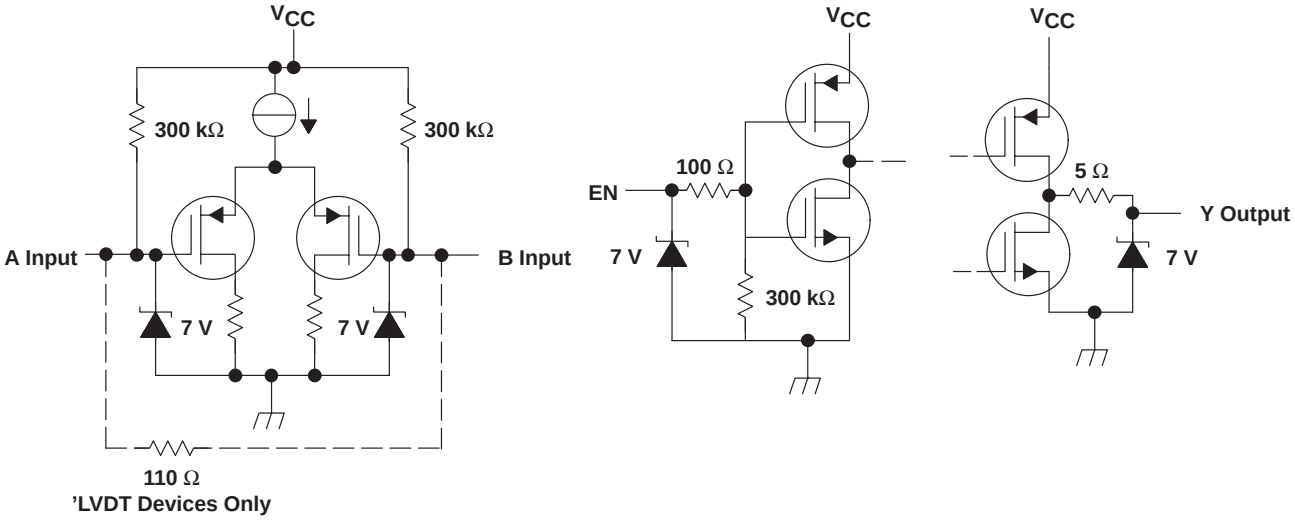
Function Table

SNx5LVD386/388 and SNx5LVDT386/388

DIFFERENTIAL INPUT	ENABLES	OUTPUT
A-B	EN	Y
$V_{ID} \geq 100$ mV	H	H
-100 mV < $V_{ID} \leq 100$ mV	H	?
$V_{ID} \leq -100$ mV	H	L
X	L	Z
Open	H	H

H = high level, L = low level, X = irrelevant,
Z = high impedance (off), ? = indeterminate

equivalent input and output schematic diagrams



absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V_{CC} (see Note 1) . . . . . –0.5 V to 4 V
Voltage range: Enables or Y . . . . . –0.5 V to V_{CC} + 2 V
A or B . . . . . –0.5 V to 4 V
Electrostatic discharge: (see Note 2)
SN65' (A, B, and GND) . . . . . Class 3, A:15 kV, B: 700 V
SN65' (All pins) . . . . . Class 3, A: 8 kV, B:600 V
SN75' (A, B, and GND) . . . . . Class 2, A:4 kV, B: 400 V
SN75' (All pins) . . . . . Class 2, A: 2 kV, B:200 V
Continuous power dissipation . . . . . See Dissipation Rating Table
Storage temperature range . . . . . –65°C to 150°C
Lead temperature 1,6 mm (1/16 in) from case for 10 seconds . . . . . 260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
2. Tested in accordance with MIL-STD-883C Method 3015.7.

DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25°C$	DERATING FACTOR‡ ABOVE $T_A = 25°C$	$T_A = 70°C$ POWER RATING	$T_A = 85°C$ POWER RATING
DBT	1071 mW	8.5 mW/°C	688 mW	556 mW
DGG	2094 mW	16.7 mW/°C	1342 mW	1089 mW

‡ This is the inverse of the junction-to-ambient thermal resistance when board-mounted (low-k) and with no air flow.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}		3	3.3	3.6	V
High-level input voltage, V_{IH}		2			V
Low-level input voltage, V_{IL}				0.8	V
Magnitude of differential input voltage, $\lvert V_{ID} \rvert$		0.1		0.6	V
Common–mode input voltage, V_{IC} (see Figure 4)		$\frac{\lvert V_{ID} \rvert}{2}$		$2.4 - \frac{\lvert V_{ID} \rvert}{2}$	V
				$V_{CC} - 0.8$	
Operating free-air temperature, T_A	SN75’	0		70	°C
	SN65’	–40		85	°C

electrical characteristics over recommended operating conditions (unless otherwise noted).

PARAMETER			TEST CONDITIONS	MIN	TYP†	MAX	UNIT
V_{ITH+}	Positive–going differential input voltage threshold		See Figure 1 and Table 1			100	mV
$V_{ITH–}$	Negative–going differential input voltage threshold		See Figure 1 and Table 1	–100			mV
V_{OH}	High–level output voltage		I_{OH} = –8 mA	2.4	3		V
V_{OL}	Low–level output voltage		I_{OL} = 8 mA		0.2	0.4	V
I_{CC}	Supply current		Enabled, No load		50	70	mA
			Disabled			3	
I_I	Input current (A or B inputs)	’LVDS	V_I = 0 V		–13	–20	µA
			V_I = 2.4 V	–1.2	–3		
		’LVDT	V_I = 0 V, other input open			–40	
			V_I = 2.4 V, other input open	–2.4			
I_{ID}	Differential input current $\lvert I_{IA} – I_{IB}\rvert$	‘LVDS	V_{IA}= 0 V, V_{IB} = 0.1V, V_{IA}= 2.4 V, V_{IB} = 2.3 V			±2	µA
I_{ID}	Differential input current $(I_{IA} – I_{IB})$	‘LVDT	V_{IA}= 0.2 V, V_{IB} = 0V, V_{IA}= 2.4 V, V_{IB} = 2.2 V	1.5		2.2	mA
$I_{I(OFF)}$	Power–off Input current (A or B inputs)	‘LVDS	V_{CC} = 0 V, V_I=2.4 V		12	±20	µA
$I_{I(OFF)}$	Power–off Input current (A or B inputs)	‘LVDT	V_{CC} = 0 V, V_I=2.4 V			±40	µA
I_{IH}	High–level input current (enables)		V_{IH} = 2 V			10	µA
I_{IL}	Low–level input current (enables)		V_{IL} = 0.8 V			10	µA
I_{OZ}	High–impedance output current		V_O = 0 V			±1	µA
			V_O = 3.6 V			10	
C_{IN}	Input Capacitance, A or B input to GND		V_{ID} = 0.4 sin 2.5E09 t V		5		pF
$Z_{(t)}$	Termination impedance		V_{ID} = 0.4 sin 2.5E09 t V	88		132	Ω

† All typical values are at 25°C and with a 3.3 V supply.

switching characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	See Figure 2	1	2.6	4	ns
t_{PHL}	Propagation delay time, high-to-low-level output	See Figure 2	1	2.5	4	ns
t_r	Differential output signal rise time	See Figure 2	500	800	1200	ps
t_f	Differential output signal fall time	See Figure 2	500	800	1200	ps
$t_{sk(p)}$	Pulse skew $(\lvert t_{PHL} – t_{PLH}\rvert)$	See Figure 2		150	600	ps
$t_{sk(o)}$	Output skew‡	See Figure 2		100	400	ps
$t_{sk(pp)}$	Part-to-part skew§	See Figure 2			1	ns
t_{PZH}	Propagation delay time, high-impedance-to-high-level output	See Figure 3		7	15	ns
t_{PZL}	Propagation delay time, high-impedance-to-low-level output	See Figure 3		7	15	ns
t_{PHZ}	Propagation delay time, high-level-to-high-impedance output	See Figure 3		7	15	ns
t_{PLZ}	Propagation delay time, low-level-to-high-impedance output	See Figure 3		7	15	ns

† All typical values are at 25°C and with a 3.3 V supply.
‡ $t_{sk(o)}$ is the magnitude of the time difference between the t_{PLH} or t_{PHL} of all drivers of a single device with all of their inputs connected together.
§ $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

PARAMETER MEASUREMENT INFORMATION

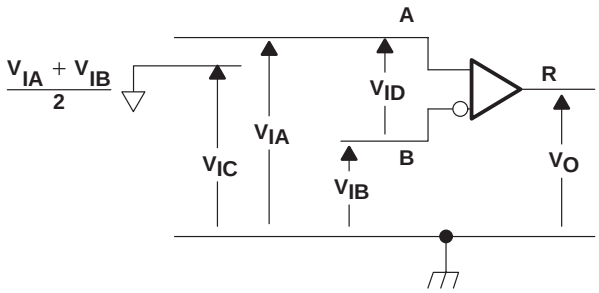
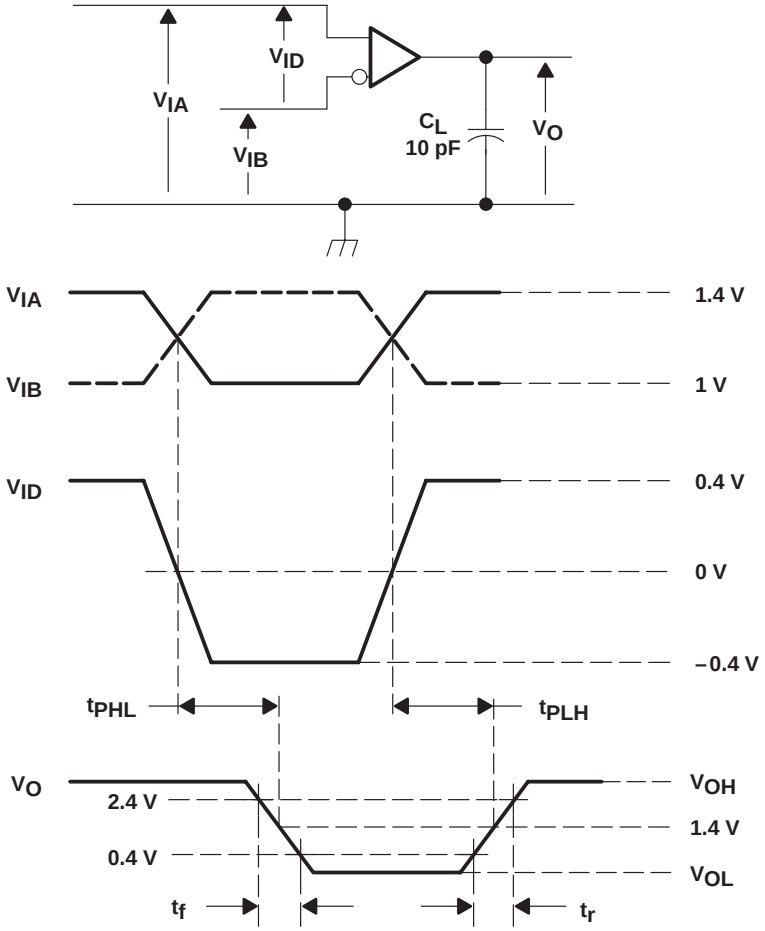


Figure 1. Voltage Definitions

Table 1. Receiver Minimum and Maximum Input Threshold Test Voltages

Applied Voltages		Resulting Differential Input Voltage	Resulting Common–Mode Input Voltage
V_{IA}	V_{IB}	V_{ID}	V_{IC}
1.25 V	1.15 V	100 mV	1.2 V
1.15 V	1.25 V	–100 mV	1.2 V
2.4 V	2.3 V	100 mV	2.35 V
2.3 V	2.4 V	–100 mV	2.35 V
0.1 V	0 V	100 mV	0.05 V
0 V	0.1 V	–100 mV	0.05 V
1.5 V	0.9 V	600 mV	1.2 V
0.9 V	1.5 V	–600 mV	1.2 V
2.4 V	1.8 V	600 mV	2.1 V
1.8 V	2.4 V	–600 mV	2.1 V
0.6 V	0 V	600 mV	0.3 V
0 V	0.6 V	–600 mV	0.3 V

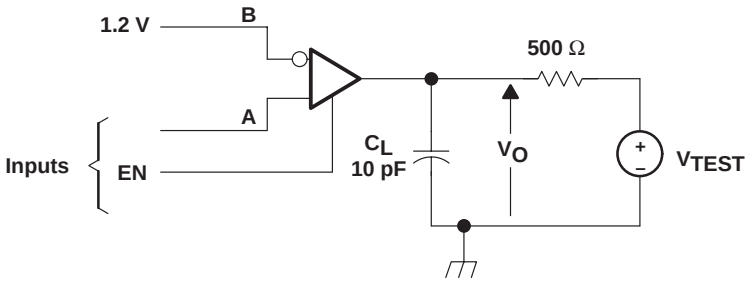
PARAMETER MEASUREMENT INFORMATION



NOTE: All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \leq 1$ ns, Pulse Repetition Rate (PRR) = 50 Mpps, Pulse width = 10 ± 0.2 ns . C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

Figure 2. Timing Test Circuit and Wave Forms

PARAMETER MEASUREMENT INFORMATION



NOTE A: All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

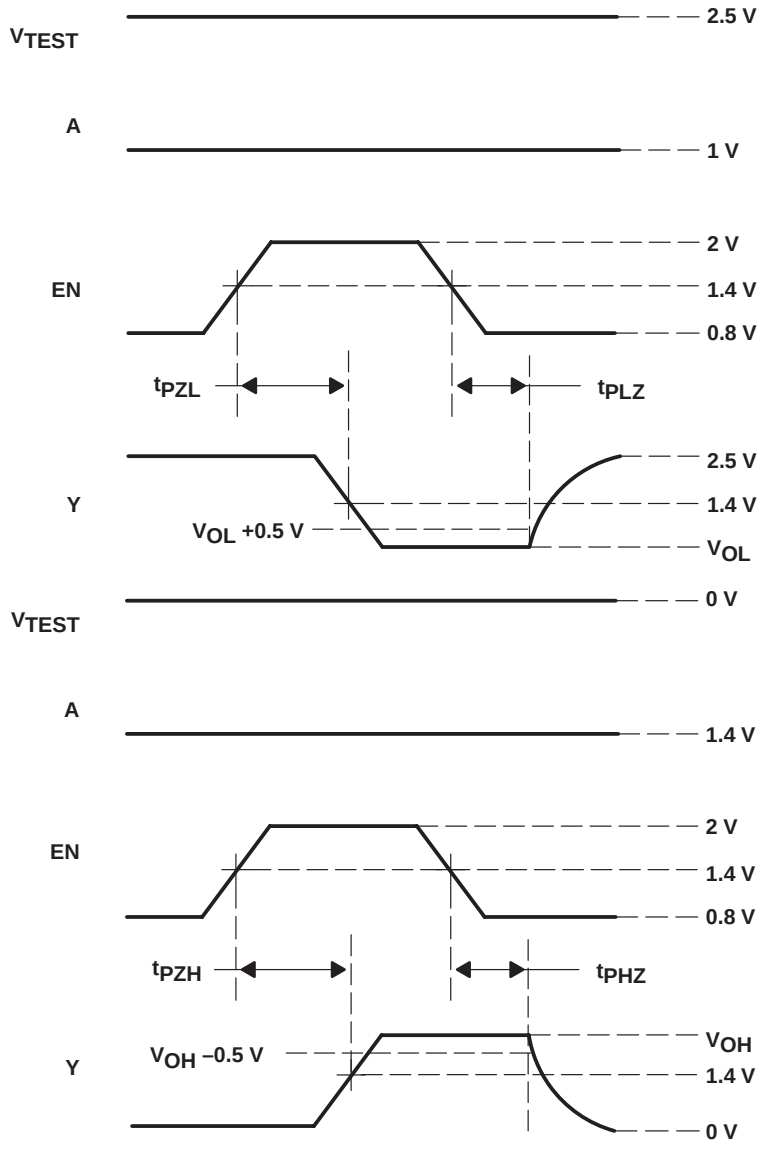


Figure 3. Enable/Disable Time Test Circuit and Wave Forms

TYPICAL CHARACTERISTICS

COMMON-MODE INPUT VOLTAGE vs DIFFERENTIAL INPUT VOLTAGE

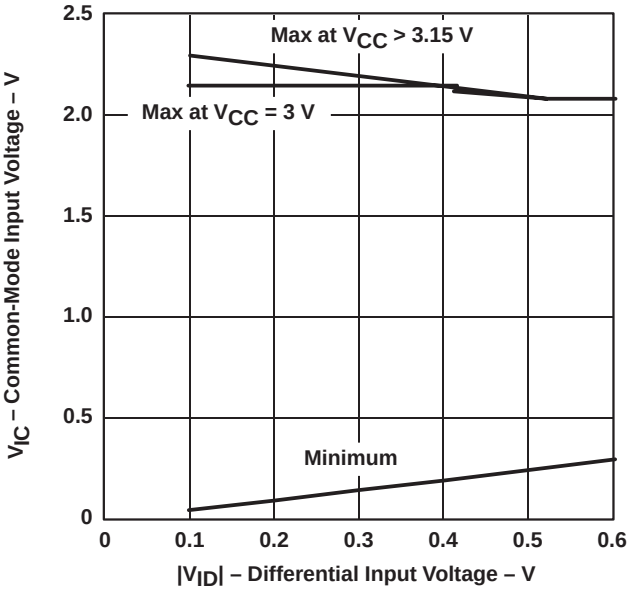


Figure 4

LVDx388 SUPPLY CURRENT vs SWITCHING FREQUENCY

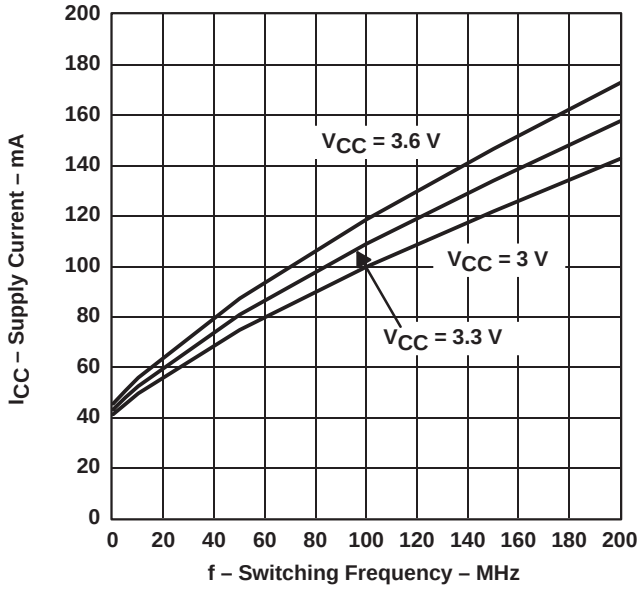


Figure 5

HIGH-LEVEL OUTPUT VOLTAGE vs HIGH-LEVEL OUTPUT CURRENT

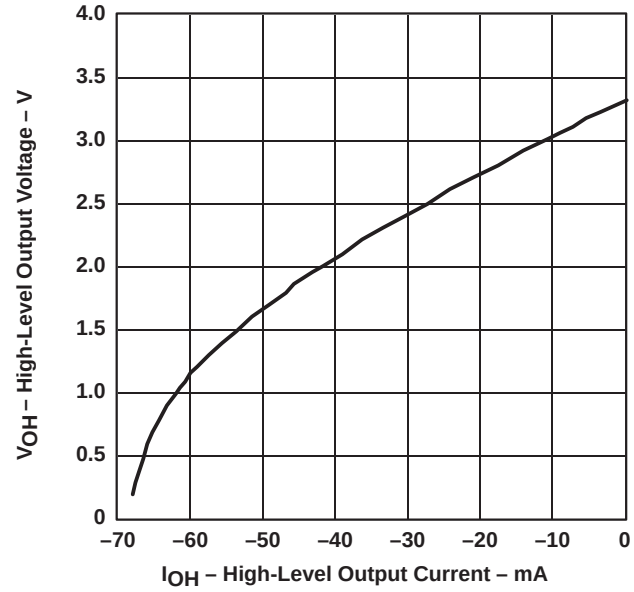


Figure 6

LOW-LEVEL OUTPUT VOLTAGE vs LOW-LEVEL OUTPUT CURRENT

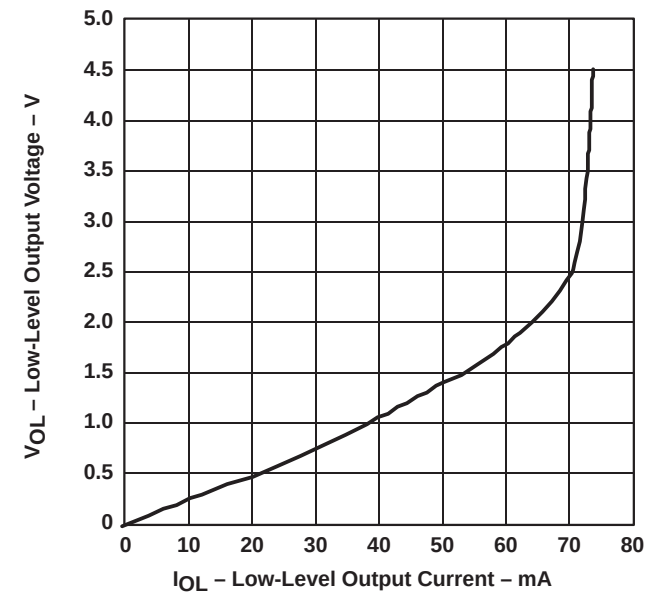


Figure 7

TYPICAL CHARACTERISTICS

LOW-TO-HIGH PROPAGATION DELAY TIME vs FREE-AIR TEMPERATURE

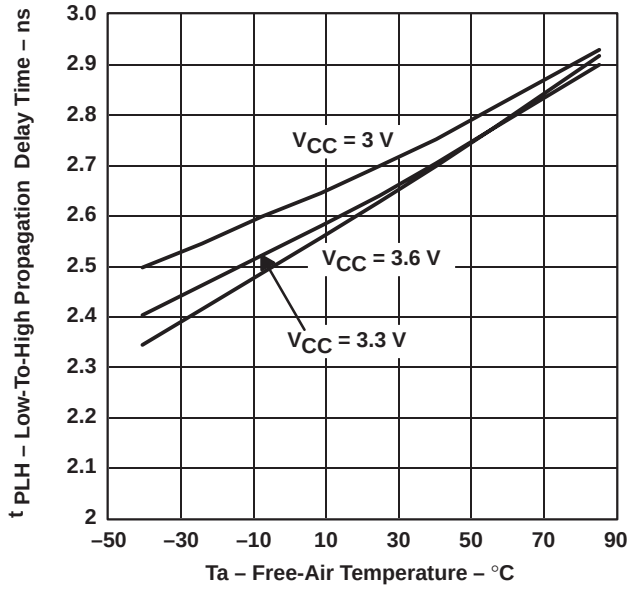


Figure 8

HIGH-TO-LOW PROPAGATION DELAY TIME vs FREE-AIR TEMPERATURE

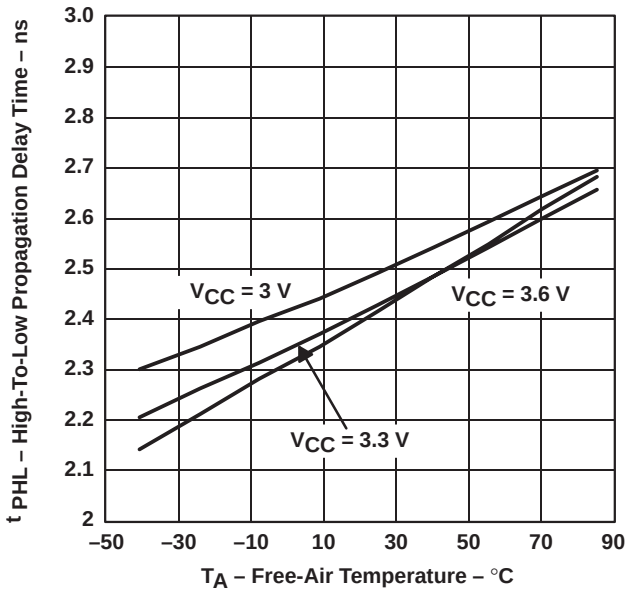


Figure 9

APPLICATION INFORMATION

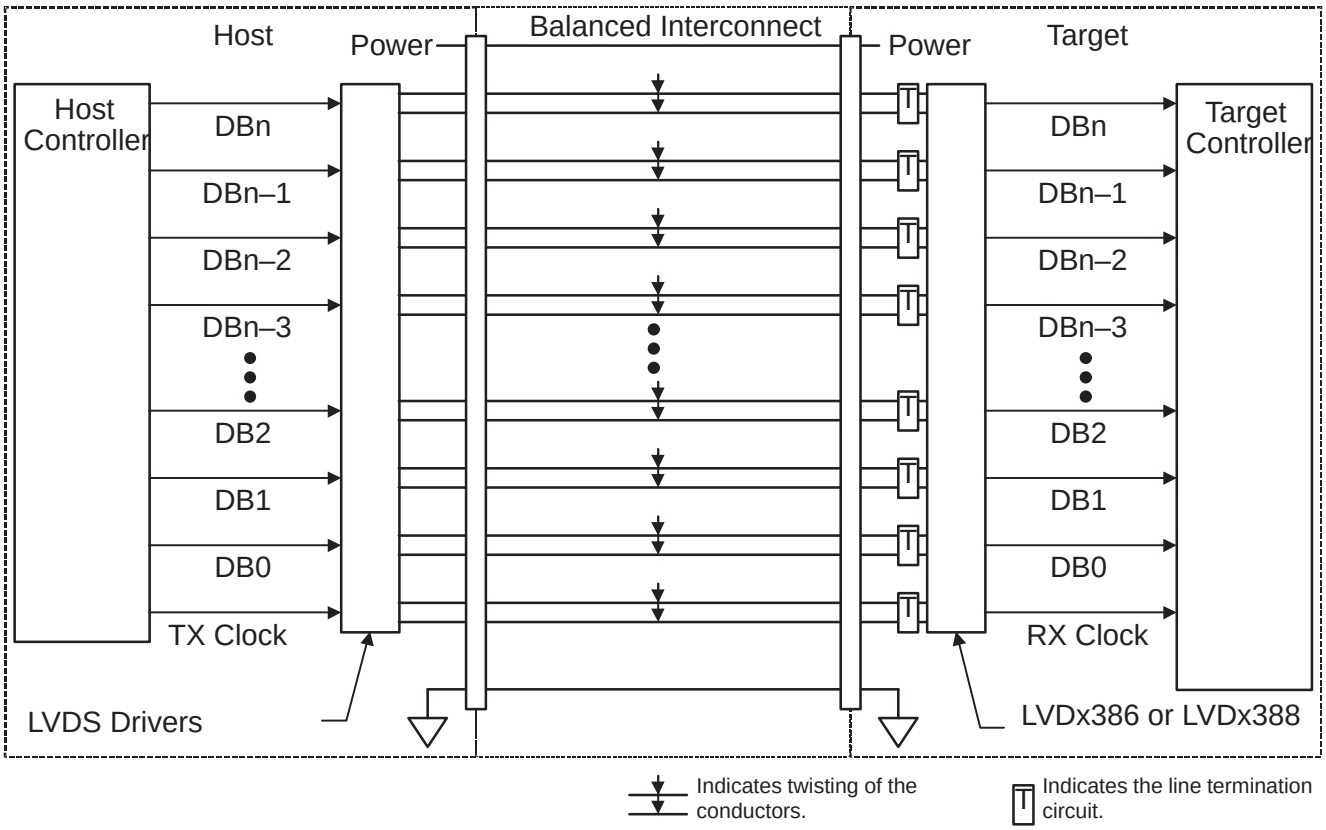


Figure 10. Typical Application Schematic

APPLICATION INFORMATION

fail safe

One of the most common problems with differential signaling applications is how the system responds when no differential voltage is present on the signal pair. The LVDS receiver is like most differential line receivers, in that its output logic state can be indeterminate when the differential input voltage is between –100 mV and 100 mV and within its recommended input common-mode voltage range. TI's LVDS receiver is different in how it handles the open-input circuit situation, however.

Open-circuit means that there is little or no input current to the receiver from the data line itself. This could be when the driver is in a high-impedance state or the cable is disconnected. When this occurs, the LVDS receiver will pull each line of the signal pair to near V_{CC} through 300-kΩ resistors as shown in Figure 10. The fail-safe feature uses an AND gate with input voltage thresholds at about 2.3 V to detect this condition and force the output to a high-level regardless of the differential input voltage.

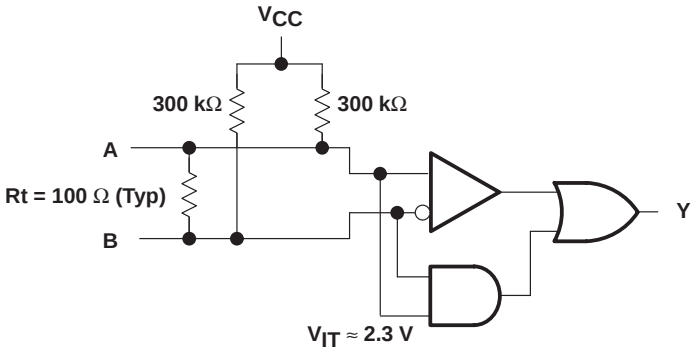


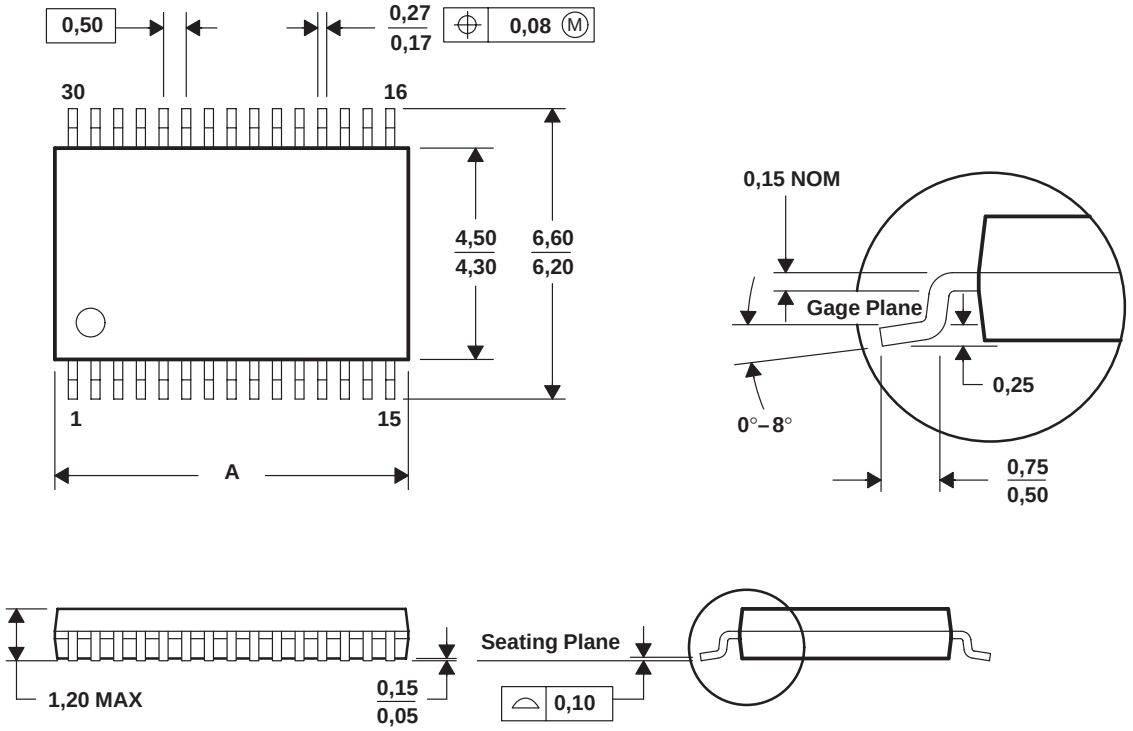
Figure 11. Open-Circuit Fail Safe of the LVDS Receiver

It is only under these conditions that the output of the receiver will be valid with less than a 100 mV differential input voltage magnitude. The presence of the termination resistor, Rt, does not affect the fail-safe function as long as it is connected as shown in the figure. Other termination circuits may allow a dc current to ground that could defeat the pull-up currents from the receiver and the fail-safe feature.

MECHANICAL DATA

DBT (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

30 PINS SHOWN



DIM \ PINS **	28	30	38	44	50
A MAX	7,90	7,90	9,80	11,10	12,60
A MIN	7,70	7,70	9,60	10,90	12,40

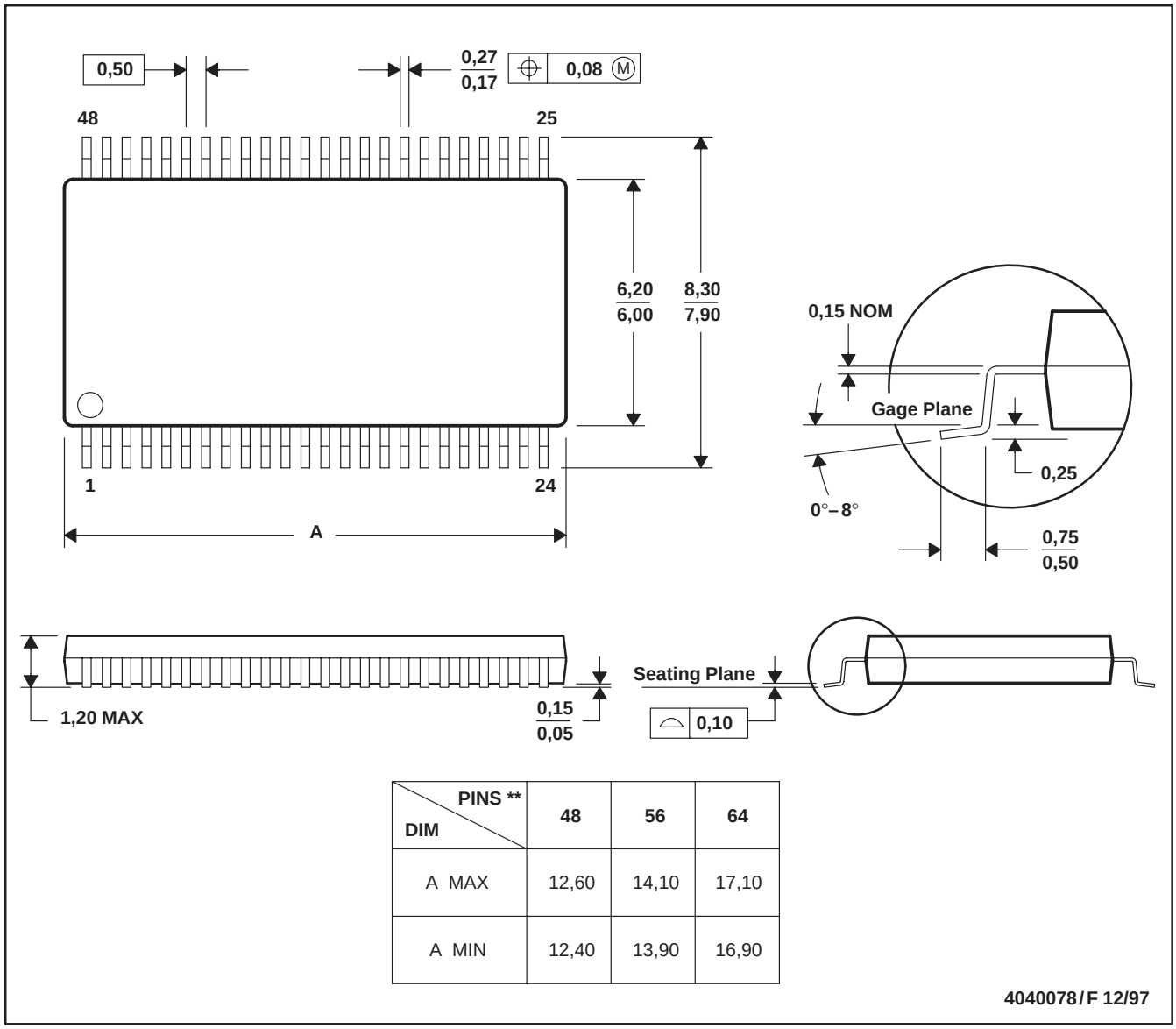
4073252/D 09/97

NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion.
D. Falls within JEDEC MO-153

MECHANICAL DATA

DGG (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

48 PINS SHOWN



DIM \ PINS **	48	56	64
A MAX	12,60	14,10	17,10
A MIN	12,40	13,90	16,90

4040078/F 12/97

NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold protrusion not to exceed 0,15.
D. Falls within JEDEC MO-153

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